Notice of References Cited Application/Control No. 10/672,551 Examiner Ben P. Sandvik Applicant(s)/Patent Under Reexamination FUNABA ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-------------------|----------------|
| * | Α | US-6,137,164 | 10-2000 | Yew et al. | 257/686 |
| * | В | US-6,630,628 | 10-2003 | Devnani et al. | 174/255 |
| * | O | US-2001/0022739 | 09-2001 | Funaba et al. | 365/63 |
| * | D | US-6,184,477 | 02-2001 | Tanahashi, Shigeo | 174/261 |
| | Е | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | Н | US- | | | |
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| | L | US- | | | |
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FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
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NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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